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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/670,869	HIRAI, JUN	
Examiner	Art Unit	
Ted M. Wang	2611	

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SEARCH NOT (INCLUDING SEARCH		')
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EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	1/4/2008	TW
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